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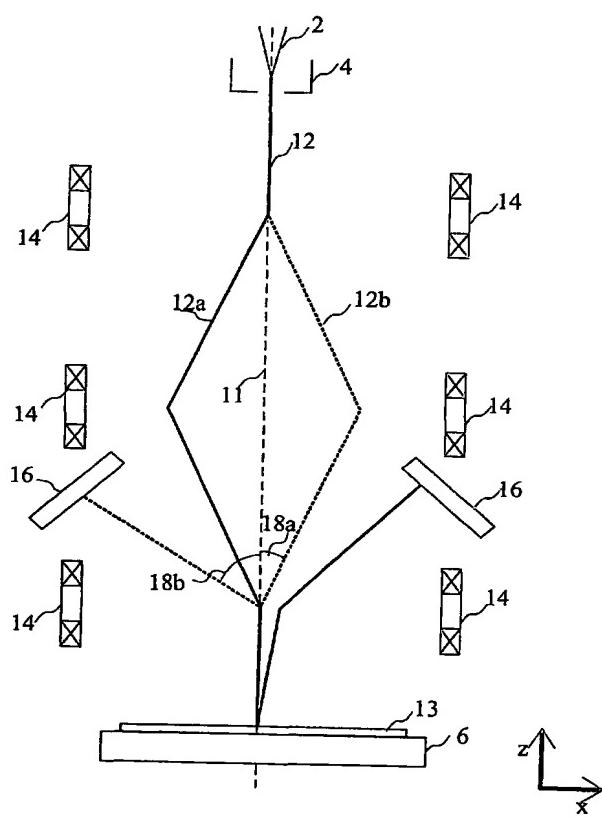
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- (71) Applicant (for all designated States except US): **ICT, INTEGRATED CIRCUIT TESTING GESELLSCHAFT FÜR HALBLEITERPRÜFTECHNIK MBH [DE/DE]**; Ammerthalstr. 20a, 85551 Heimstetten (DE).
- (72) Inventor; and
- (75) Inventor/Applicant (for US only): **FROSIEN, Juergen** [DE/DE]; Kufsteinerstr. 16a, 85521 Riemerling (DE).
- (74) Agents: **ZIMMERMANN, Gerd et al.**; Zimmermann & Partner, P.O. Box 330 920, 80069 Munich (DE).
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(54) Title: CHARGED PARTICLE BEAM DEVICE WITH DETECTION UNIT SWITCH AND METHOD OF OPERATION THEREOF



(57) Abstract: The invention provides a charged particle beam device and a method of operation thereof. An emitter (2) emits a primary charged particle beam (12). Depending on the action of a deflection system, which comprises at least three deflection stages (14), it can be switched between at least two detection units (16, 44). Further, beam shaping means (15; 41) is provided and a lens for focusing at the primary charged particle beam on a specimen.



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